

SEAGATE FireCuda 120 SSD Perfect for Gaming Use and Video Editing Owner's Manual

Home » Seagate » SEAGATE FireCuda 120 SSD Perfect for Gaming Use and Video Editing Owner's Manual



SEAGATE FireCuda 120 SSD Perfect for Gaming Use and Video Editing Owner's Manual





Contents

- 1 Introduction
- 2 Specifications
 - 2.1 Performance
 - 2.2 Environmental Conditions
- 3 Mechanical Information
- **4 Pin and Signal Descriptions**
- **5 Supported ATA Command List**
- **6 SMART Support**
- **7 Feature Details**
- 8 Seagate Technology Support

Services

- 9 Documents / Resources
 - 9.1 References
- **10 Related Posts**

Introduction

Feature	Description	
Capacity (User)	500 GB, 1000 GB, 2000 GB, 4000 GB	

Certificati ons, Eco- Complianc e	CE, UL, FCC, BSMI, KCC, Microsoft WHCK, VCCI, CBn RoHS					
Dimension s	(69.85±0.25) x (100±0.25) x (Max. 7) mm SSD outer case can support s uitable Z-height for various ho st situations.					
Endurance	 500 GB 700 Total Bytes Written (TBW) 1000 GB 1400 TBW 2000 GB 2800 TBW 4000 GB 5600TBW Endurance rating valid for SS D Life Remaining > 1% (SMA RT E7h>1). See Section 2.5, Reliability/Endurance. 					
Form Fact or	2.5-inch Standard SSD					
Interface C ompliance	 Fully compliant with ATA-8/ACS-3 Standard Compliant with SATA Revision 3.2 Supported protocol AHCI and ASC2 command set Compatible with SATA 1.5 Gbps, 3 Gbps, and 6Gbps interfaces n PIO, DMA, UDMA (up to 6 m odes, dependent on host) supported Native Command Queuing (NCQ): up to 32 commands Data Set Management Command Trim support 					
NAND	3D TLC					
Operating Systems	 Windows® 7 (64 bit), 8.1 (64 bit), and Windows 10 (64 bit) Ubuntu 16.10 					
Performan ce Rando m	 Read: Up to 100,000 IOPS Write: Up to 90,000 IOPS Actual performance might var y depending on use condition s and environment. See Section 2.2, Performance. 					
Performan ce Sequen tial	Actual performance might vary depending on the capacity, use conditions and environment. See Section 2.2, Performance.					
Power Consumpti on	 Active mode: < 2800 mW Idle mode: < 150 mW DEVSLP: 5 mW Based on 4000 GB SSD. Results vary with capacity and mode. 					

Power Los s Data Pro tection		To protect your data, you must send a Standby Immediate command (0xE1h) before you remove power. The FireCuda 120 SSD does not provide data protection for a sudden power loss.			
Power Ma nagement	• Host-initiated power managementn, Device-initiated power managementn, HIPM/DEVSLP Mo				
Reliability		End-to-end data path protectionn MTBF: 1.8 million hoursn UBER: 1 error in 1016 bits read			
Shock and \	/ibratio	Shockn Non-Operating: 1,500 G, at 0.5 ms			
n		Vibrationn Non-Operating: 1.52 G _R _{MS} , (20 to 80 Hz, Frequency)	See <u>Section 2.4, Environmental Conditions</u> .		
Temperature Range (Operating)		0°C to 70°Cn Temperature Sensor (SMART Attribute ID C2h)			
Voltage		5V±5%			
Warranty		Five years, or when the device reaches Host TBW, whichever happens first. Endurance rating valid for SSD Life Remaining > 1% (SMART E7h>1).			
Weight		50 g, 1.76 Oz ±5%			

Specifications

Models and Capacity

Table 2 Models and Capacity

Model Names	User Capacity	
ZA500GM10001	500 GB	
ZA1000GM10001	1000 GB	
ZA2000GM10001	2000 GB	
ZA4000GM10001	4000 GB	

NOTE: About capacity:

- Sector Size: 512 Bytes
- User-addressable LBA count = ((97696368) + (1953504 x (Desired Capacity in Gb-50.0)) From International Disk Drive Equipment and Materials Association (IDEMA) (LBA1-03_standard.doc)

Performance

Table 3 Random and Sequential Read and Write Performance

Parameter	500 GB	1000 GB	2000 GB	4000 GB
Sequential Read MB/s	560 MB/s	560 MB/s	560 MB/s	560 MB/s
Sequential Write MB/s	540 MB/s	540 MB/s	540 MB/s	540 MB/s
Random Read (IOPS)	100,000	100,000	100,000	100,000
Random Write (IOPS)	90,000	90,000	90,000	90,000

NOTE: About performance:

- Fresh out of box (FOB) performance obtained on newly formatted drive. Performance may vary based on the SSD's firmware version, system hardware, and configuration.
- Performance is based on CrystalDiskMark v.6.0.0 ×64 on Windows 10 host.

Power Consumption

Table 4 Power Consumption

	500 GB	1000 GB	2000 GB	4000 GB
Read (mW)	2300	2400	2600	2800
Write (mW)	2300	2400	2600	2800
Idle (mW)	120	135	140	150
Slumber (mW)	35	55	60	65
DEVSLP (mW)	5	5	5	5

NOTE: About power consumption:

- The average value of power consumption is based on 100% conversion efficiency.
- The measured power voltage is 5 V.
- Measured under ambient temperature.
- Sequential Read/Write is measured while testing 4000 MB five times by CrystalDiskMark.
- Power Consumption can differ according to flash configuration and platform.

Environmental Conditions

Table 5 Temperature, Humidity, Shock

Specification	Value	
Temperature Operating (case temperature at specific airflow) Non-operating	0°C to 70°C -40°C to 85°C	
Humidity Operating Non-operating (storage)	90% 93%	
Shock Non-operating	1,500 G, duration 0.5 ms	
Vibration Non-operating	1.52 GRMS, (20Hz to 80Hz, Frequency)	

NOTE: Temperature is measured without condensation. Operating mode temperature is measured by temperature sensor, SMART Attribute C2h.

NOTE: Shock and vibration results assume that the SSD is mounted securely with the input vibration applied to the SSD mounting. These specifications do not cover connection issues that may result from testing at this level. The measured specification is in root mean square (RMS) form.

- Non-operating Shock. The limits of non-operating shock applies to all conditions of handling and transportation. This includes both isolated SSD and integrated SSDs. Shock may be applied in the X, Y, or Z-axis.
- Non-Operating Vibration. The limits of non-operating vibration shall apply to all conditions of handling and transportation. This includes both isolated SSD and integrated SSDs. Vibration may be applied in the X, Y, or Z-axis.

Reliability/Endurance

Table 6 Reliability/Endurance

Specification	Value			
Mean time between failures (MTBF)	1.8 million hours			
Bit Error Rate	1 error in 1016 bits read			
Endurance	700 GB TBW1400 GB TBW2800 GB TBW5600 GB TBW			

NOTE: About endurance

- The SSD achieves the specified MTBF in an operational environment that complies with the operational temperature range specified in this manual. Operating temperatures are measured by temperature sensor, SMART Attribute ID C2h.
- Endurance rating valid for SSD Life Remaining > 1% (SMART E7h>1).

• Endurance is characterized while running Client JESD219A workload (per JESD218A specification).

Mechanical Information

Dimensions and Weight

• Weight: 50 g, 1.76 Oz +/- 5%

• Height: Maximum, 7 mm+0.10/-0.30

Width: 69.85 mm±0.25 mmLength: 100.10 mm±0.25 mm

Figure 1 FireCuda 120 SSD Enclosure

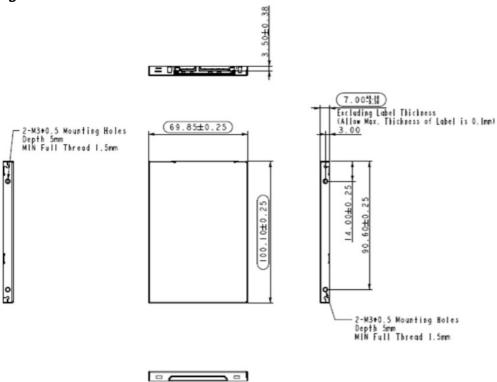
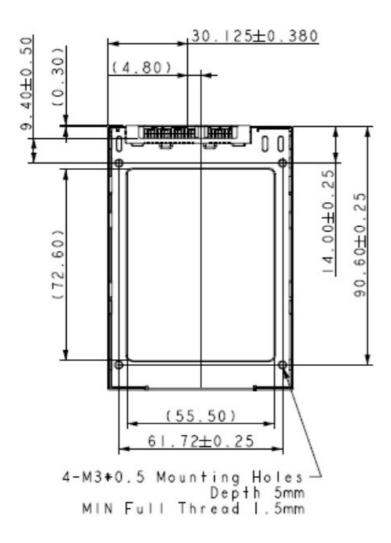


Figure 2 FireCuda 120 SSD



Pin and Signal Descriptions

Signal Pin Definitions

Table 7 Serial ATA Connector Pin Signal Definitions

Pin	Name	Definition
S1	Ground	Ground
S2	A+	Differential signal pair A+ and A-
S3	A-	Differential Signal pail A+ and A-
S4	Ground	Ground
S5	B-	Differential signal pair B- and B+
S6	B+	Differential signal pail D- and D+
S7	Ground	Ground

NOTE Key and spacing separate the signal and power segments.

Power Pin Definitions

Table 8 Power Pin Definitions

Pin	Function	Definition
P1	not used	Not Used (3.3 V)
P2	V33	Not Used (3.3 V)
P3	DEVSLP	SATA PHY Power Control
P4	GND	Ground
P5	GND	Ground
P6	GND	Ground
P7	V5	5 V Power, Precharge
P8	V5	5 V Power
P9	V5	5 V Power
P10	GND	Ground
P11	Reserved	Reserved
P12	GND	Ground
P13	not used	Not Used (12 V pre-charge)
P14	V12	Not Used (12 V)
P15	V12	Not Used (12 V)

NOTE: About Power Pin Signal Definitions:

- Key and spacing separate the signal and power segments.
- Uses 5 V power only; 3.3 V (P1-P2) and 12 V (P13-P15) power are not used.

Supported ATA Command List

The FireCuda 120 SSD complies with ATA-8/ACS-3. All mandatory and many optional commands and features are supported.

ATA Feature Set

The following table summarizes the ATA feature set and commands that the FireCuda 120 SSD supports.

Table 9 ATA Feature Set

Feature	Supported
48-Bit Address feature set	Yes
General feature set	Yes
Native Command Queuing (NCQ) feature set	Yes
Power Management feature set	Yes
Security feature set	Yes
SMART feature set	Yes

ATA Command Description

The following table shows the ATA commands supported

Table 10 ATA Command Description

Op-Code	Supp ort	Command Description	0	Op-Code		Op-Code		Suppo rt	Command Description
00h	Y	NOP	B6 h	12 h	_	_	NV Cache: QUERY NV CACHE PIN NED SET DMA EXT		
03h	_	CFA Request Extended E rror	B6 h	13 h	_		NV Cache: QUERY NV CACHE MIS SES DMA EXT		
06h	Y	Data Set Management	B6 h	14 h	_	_	NV Cache: FLUSH NV CACHE		
08h	_	Device Reset	C4 h	_	_	Y	Read Multiple		
0Bh	_	Request Sense Data EXT	C5 h	_	_	Υ	Write Multiple		

10h	Y	Recalibrate	C6 h	_	_	Y	Set Multiple Mode
11h to 1Fh	_	Recalibrate	C7	_	_		Read DMA Queued
20h	Y	Read Sectors C8 h — Y Read DMA					Read DMA
21h	Y	Read Sectors without Retr	9h	_	_	_	Read DMA Without Retry
22h	_	Read Long	CA h	_	_	Y	Write DMA
23h	_	Read Long Without Retry	CB h	_	_	Y	Write DMA Without Retry
24h	Y	Read Sectors EXT	CC h	_	_	_	Write DMA Code
25h	Y	Read DMA EXT	CD h	_	_	_	CFA Write Multiple Without Erase
26h —	_	Read DMA Queued EXT	CE h	_	_	Υ	Write Multiple FUA EXT
27h —	Y Read Native Max Address D1 h — — Check Media Card Type		Check Media Card Type				

29h	_	Y	Read Multiple EXT	DA h	_	_	_	Get Media Status
2A h	_	_	Read Stream DMA EXT	DE h	_	_	_	Media Lock
2B h	_	_	Read Stream EXT	DF h	_	_	_	Media Unlock
2F h	_	Y	Read Log EXT	E0 h	_	_	Y	Standby Immediate
30h	_	Υ	Write Sectors	E1 h	_	_	Y	Idle Immediate
31h	_	Υ	Write Sectors without Retr y	E2 h	_	_	Y	Standby
32h	_	_	Write Long	E3 h	_	_	Y	Idle
33h	_	_	Write Long Without Retry	E4 h	_	_	Y	Read Buffer
34h	_	Υ	Write Sectors EXT	E5 h	_	_	Y	Check Power Mode
35h	_	Υ	Write DMA EXT	E6 h	_	_	Υ	Sleep

36h	_		Write DMA Queued EXT	E7 h	_	_	Y	Flush Cache
37h	_	Y	Set Max Address EXT	E8 h	_	_	Y	Write Buffer
38h	_	_	CFA Write Sectors Withou t Erase	E9 h	_	_	Y	Read Buffer DMA
39h	_	Y	Write Multiple EXT	EA h	_	_	Y	Flush Cache EXT
3A h	_	_	Write Stream DMA EXT	EB h	_	_	Y	Write Buffer DMA
3B h	_	_	Write Stream EXT	EC h	_	_	Y	Identify Device
3C h	_	_	Write Verify	ED h	_	_	_	Media Eject
3D h	_	Y	Write DMA FUA EXT	EE h	_	_	_	Identify Device DMA
3E h	_	_	Write DMA Queued FUA EXT	EF h	01 h	_	_	Set Features: Enable 8-bit PIO Tran sfer Mode (CFA feature set only)
3F h	_	Y	Write Log EXT	EF h	02 h	_	Υ	Set Features: Enable Write Cache

40 h	_	Y	Read Verify Sectors	E Fh	03 h	_	Y	Set Features: Set transfer mode bas ed on value in Count field.
41h	_	Υ	Read Verify Sectors witho ut Retry	EF h	05 h	_	_	Set Features: Enable advanced pow er man- agement.
42h	_	Υ	Read Verify Sector(s) EXT	EF h	06 h	_	_	Set Features: Enable Power-Up In S tandby fea- ture set.
44h	_	_	Reserved	EF h	07 h	_	_	Set Features: Power-Up In Standby feature set device spin-up.
45h	_	0	Write Uncorrectable EXT	EF h	0A h	_	_	Set Features: Enable CFA power m ode 1.
47h	_	Υ	Read Log DMA EXT	EF h	0B h	_	_	Set Features: Enable Write-Read-V erify feature set
50h	_	_	Format Track	EF h	10 h	01 h	_	Set Features: Enable use of Serial A TA fea- ture
51h	_	_	Configure Stream	EF h	10 h	02 h	Y	Set Features: Enable DMA Setup FI S Auto-Acti- vate optimization
57h	_	Υ	Write Log DMA EXT	EF h	10 h	03 h	Y	Set Features: Enable Device-initiate d interface power state (DIPM) trans itions.
60h	_	Υ	Read FPDMA Queued	EF h	10 h	04 h	_	Set Features: Enable use of Serial A TA feature

61h	_	Y	Write FPDMA Queued	EF h	10 h	05 h	_	Set Features: Enable use of Serial A TA feature
70h	_	Υ	Seek	EF h	10 h	06 h	0	Set Features: Enable Software Setti ngs Preservation (SSP)
71- 76h	_	_	Seek	EF h	10 h	07 h	Υ	Set Features: Enable Device Autom atic Partial to Slumber transitions
77h	_	Υ	Set Date And Time Ext	EF h	10 h	09 h	0	Set Features: Enable Device Sleep
78h	_	Υ	Accessible Max Address Configuration	EF h	42 h	_	_	Set Features: Enable Automatic Acoustic Management feature set.
79- 7F h	_	_	Seek	EF h	43 h	_	_	Set Features: Set Maximum Host Int erface Sector Times.
87h	_	_	CFA Translate Sector	EF h	44 h	_	_	Set Features: Vendor Specific ECC byte
90 h	_	Y	Execute Device Diagnosti c	EF h	55 h	_	Y	Set Features: Disable read look-ahe ad feature
91h	_	Y	Initialize Device Paramete rs	EF h	5D h	_	_	Set Features: Enable release interru pt
92h	_	Υ	Download Microcode	EF h	5E h		_	Set Features: Enable service interru pt

93h	_	Y	Download Microcode DM A	EF h	5F h	_	_	Set Features: Enable NDRQ Featur e
94 h	_	_	Standby Immediate	EF h	66 h	_	Y	Set Features: Disable reverting to p ower-on defaults
95 h	_	_	Idle Immediate	EF h	81 h	_	_	Set Features: Disable 8-bit PIO tran sfer mode (CFA feature set only)
96h	_	_	Standby	EF h	82 h	_	Υ	Set Features: Disable write cache
97h	_	_	Idle	EF h	85 h		Y	Set Features: Disable advanced po wer management
98h	_	_	Check Power Mode	EF h	86 h		_	Set Features: Disable Power-Up In Standby feature set
99h	_	_	Sleep	EF h	8A h		_	Set Features: Disable CFA power m ode
A0 h	_	_	Packet	EF h	8B h		_	Set Features: Disable Write-Read-V erify feature set
A1 h			Identify Packet Device	Efh	90 h	01 h		Set Features: Disable use of Serial ATA feature.
A2 h	_	_	Service	Efh	90 h	02 h	Υ	Set Features: Disable DMA Setup FI S Auto-Acti- vate optimization.

B0 h	D0 h	Y	SMART: Read Data		90 h	03 h	Y	Set Features: Disable Device-initiate d interface power state (DIPM) trans itions.
B0 h	D1 h	Y	SMART: Read Attribute T hresholds	EF h	90 04 h h		_	Set Features: Disable use of Serial ATA feature.
B0 h	D2 h	Y	SMART: Enable/disable A utosave	EF h	90 h	05 h	-	Set Features: Disable use of Serial ATA feature
B0 h	D3 h	Y	SMART: Save Attribute V alues	EF h	90 h	06 h	Υ	Set Features: Disable Software Setti ngs Preservation (SSP)
B0 h	D4 h	Y	SMART: Execute Off-line I mmediate	EF h	90 h	07 h	Y	Set Features: Disable Device Autom atic Partial to Slumber transitions
B0 h	D5 h	Y	SMART: Read Log	EF h	90 h	09 h	0	Set Features: Disable Device Sleep
B0 h	D6 h	Y	SMART: Write Log	EF h	AAh		Υ	Set Features: Enable read look- ahead feature
B0 h	D8 h	Y	SMART: Enable Operations	EF h	BBh		-	Set Features: Default ECC byte
B0 h	D9 h	Y	SMART: Disable Operations	EF h	(:'2h		_	Set Features: Disable Automatic Ac oustic Management feature set
B0 h	DA h	Y	SMART: Return Status	EF h	C3h		_	Set Features: Enable/Disable the S ense Data Reporting feature set

B0 h	DB h	Υ	SMART: Enable/disable A utomatic Off-line	EF h	CCh	Y	Set Features: Enable reverting to po wer-on defaults
B0 h	E0 h	_	SMART: Vendor specific	EF h	DDh	-	Set Features: Disable release interr upt
B1 h	C0 h	Υ	DEVICE CONFIGURATIO N: Restore	EF h	DEh	_	Set Features: Disable SERVICE interrupt
B1 h	C1 h	Υ	DEVICE CONFIGURATIO N: FreezeLock	EF h	DFh	_	Set Features: Disable NDRQ Featur e
B1 h	C2 h	Y	DEVICE CONFIGURATIO N: Identify	F1h		Y	Security Set Password
B1 h	C3 h	Υ	DEVICE CONFIGURATIO N: Set	F2h		Y	Security Unlock
B1 h	C4 h	Υ	DEVICE CONFIGURATIO N: Identify DMA	F3h		Υ	Security Erase Prepare
B1 h	C5 h	Υ	DEVICE CONFIGURATIO N: Set DMA	F4h		Υ	Security Erase Unit
B4 h	000 0h	0	SANITIZE DEVICE: Saniti ze Status Ext	F5h		Y	Security Freeze Lock
B4 h	001 1h	0	SANITIZE DEVICE: Crypt o Scramble Ext	F6h		Y	Security Disable Password

B4 h	001 2h	0	SANITIZE DEVICE: Block Erase Ext	F8h		Y	Read Native Max Address
B4 h	001 4h	0	SANITIZE DEVICE: Over write Ext	F9 h	00h	Y	SET MAX: Set Max Address
B4 h	002 0h	0	SANITIZE DEVICE: SANI TIZE FREEZE LOCK EXT	F9 h	01h	Υ	SET MAX: SET MAX PASSWORD
B4 h	004 0h	0	SANITIZE DEVICE: SANI TIZE ANTIFREEZE LOCK EXT	F9 h	02h	Y	SET MAX: SET MAX LOCK
B6 h	00h	_	NV Cache: SET NV CACH E POWER MODE EXT	F9 h	03h	Y	SET MAX: SET MAX UNLOCK
B6 h	01h	-	NV Cache: RETURN FRO M NV CACHE POWER M ODE EXT	F9 h	04h	Y	SET MAX: SET MAX FREEZE LOC
B6 h	10h	_	NV Cache: ADD LBA(S) T O NV CACHE PINNED S ET DMA EXT	F9 h	05h	Y	SET MAX: SET MAX SET PASSWO RD DMA
B6 h	11h	_	NV Cache: REMOVE LBA (S) FROM NV CACHE PI NNED SET DMA EXT	F9 h	06h	Υ	SET MAX: SET MAX UNLOCK DMA

SMART Support

The FireCuda 120 SSD supports the SMART command set.

SMART ID

	0	1	2	3	4	5	6	7	8	9	10	11	Thres				
Description	ID	Flag	g	Valu e	Wors e	DATA							hold				
Number of Acc umula- tion ofU ncorrectable Er ror	0 1 h	0B h	00h	64h	64h	l	UNC error count from Host		count from		count from		0	0	0	0	32h
Power-On hour s Count	0 9 h	12 h	00h	64h	64h	Power on hour		0	0	0	0	0	00h				
Drive Power Cy cle Count	0 C h	12 h	00h	64h	64h	Power	ver on/off cycles		Power on/off cycles 0		0	0	0	00h			
Spare Blocks A vailable	1 0 h	12 h	00h	64h	64h	ks Ava	Availabl		pare Bloc s Availabl byplane		0	0	0	0	00h		
Remaining Spa re Blocks	1 1 h	12 h	00h	64h	64h	Rema Spare ks byp	Bloc	0	0	0	0	0	00h				
SATA PHY Erro r Count	A 8 h	12 h	00h	64h	64h	SATA unt	PHY e	error	со	0	0	0	00h				
Bad Block Cou nt (Early / Later	A A h	03 h	00h	Notea		Block	Early Bad Block coun t by allplan e		0	Later Bad countby a		0	0Ah				
Erase count (av erage, max, era se count)	A D h	12 h	00h	64h	64h	Max Erase Count		Ave ge ase unt	Er eCo	Least Era	se Count	0	00h				
Unexpected Po wer Loss count	A E h	12 h	00h	64h	64h	Numb			0	0	0	00h					

Wear Range de Ita	B 1 h	00 h	00h	00h	00h	Note b	1 ()		0	0		0		0		00h	
Unexpected Po wer Loss Count	C 0 h	12 h	00h	64h	64h	1	number of accident al power loss count			0 0				0		00h	
Temperature(on ly Toshiba or th ermo sensor e mbedded)	C 2 h	23 h	00h	127- Curr e nt Tem p	127- Highe st val ue	Currer mp	Current Te mp Lowes t Tem p			Highest Temp				0		39h	
Number of accumula- tion CRC error(read /write data FIS CRC error)	D A h	0 Bh	00 h	64h	64h	CRC	Error (Cour	nt	0	0		0		32	2h	
SSD life remain ing	E 7 h	13 h	00h	64h	64h	Note c	0	0	0	0	1	ro ttli glevel	0		00	h	
Read Failure Bl ock Count	E 8 h	13 h	00h	64h	64h	Flash unt	Read	Fail (Co	Raw Read Error Rate	0 0				00	h	
Lifetime Writes to Flash (G Unit)	E 9 h	0B h	00h	64h	64h	Lifetim	Lifetime Writes to Flash by GByte 0			lash by GByte					00	h	
Lifetime Writes to Flash (Sector Unit)	E B h	0B h	00h	64h	64h	Lifetim	Lifetime Writes to Flash by Sector 0				00	h					
NAND read (Se ctors)	E A h	0B h	00h	64h	64h	NAND	NAND read (Sectors) 0				00	h					
Host Writes (G Unit)	F 1 h	12 h	00h	64h	64h	Lifetime Writes from Host by G						yte	0		00	h	
Host Reads (G Unit)	F 2 h	12 h	00h	64h	64h	Lifetim	ne Rea	ıds fı	Host by Gbyte				n Host by Gbyte 0			00	h

- a. Bad Block Count (Early / Later) ID170. Value = (Remaining Spare Blocks by plane)/(Spare Blocks Available by plane) *100. This formula calculates percentage of spare block. Value is between 100 and 0.
- b. Wear Range Delta ID 177. Value = (max erase count least erase count) / (P-E Cycle) *100 (percentage).
- c. SSD Life Remaining ID 231. Value = 100 ((average erase count / Rated PE Cycle) * 100)

Feature Details

Flash Management

1. Error Correction Code (ECC)

Flash memory cells deteriorate with use, which might generate random bit errors in the stored data. The FireCuda 120 SSD applies the 340 bit/2 KB LDPC (Low Density Parity Check) of ECC algorithm, which detects and corrects errors that occur during read process, ensures data is read correctly, and protects data from corruption.

2. Wear Leveling

NAND flash devices can undergo only a limited number of program/erase cycles. Commonly, areas of the flash media are not used evenly. If some areas are updated more frequently than others, this reduces the lifetime of the device. Wear Leveling extends the life of the NAND Flash by evenly distributing write and erase cycles across the media. Seagate's advanced Wear Leveling algorithm spreads the flash usage throughout the whole flash media area. Implementing dynamic and static Wear Leveling algorithms improves the life expectancy of the NAND flash.

3. Bad Block Management

Bad blocks do not function properly and they can contain more invalid bits. This can make stored data unstable and bad block reliability is not guaranteed. Blocks identified and marked as bad by the manufacturer are called "Early Bad Blocks". Bad blocks that develop during the lifespan of the Flash are called "Later Bad Blocks". Seagate's bad block management algorithm detects the factory-produced bad blocks and manages bad blocks that appear with use. This practice prevents data from being stored in bad blocks and improves data reliability

4. TRIM

The TRIM feature improves the read/write performance and speed of SSDs. SSDs cannot overwrite existing data, so the available space becomes smaller with each data block use. The TRIM command tells the SSD (through the operating system) which data blocks can be removed permanently because they are no longer in use. The SSD erases these unused data blocks.

5. SMART

SMART, stands for Self-Monitoring, Analysis, and Reporting Technology, is an open standard that allows an SSD to automatically detect its health and report potential failures. When SMART records a failure, users can replace the drive to prevent unexpected outage or data loss. SMART can also inform users of impending failures while there is still time to copy data to another device.

Seagate Technology Support Services

For Internal SSD Support, visit: https://www.seagate.com/support/products/

For Firmware Download and Tools Download for Secure Erase, visit:

https://www.seagate.com/support/downloads/

For information regarding online support and services, visit: http://www.seagate.com/contacts/

For information regarding Warranty Support, visit: http://www.seagate.com/support/warranty-and-replacements/

For information regarding data recovery services, visit:

http://www.seagate.com/services-software/seagate-recovery-services/recover/

For Seagate OEM and Distribution partner and Seagate reseller portal, visit: http://www.seagate.com/partners

Documents / Resources



SEAGATE FireCuda 120 SSD Perfect for Gaming Use and Video Editing [pdf] Owner's Man

FireCuda 120 SSD Perfect for Gaming Use and Video Editing, FireCuda 120 SSD, Perfect for Gaming Use and Video Editing, Gaming Use and Video Editing, Use and Video Editing, Video Editing, Editing

References

- 9 The Leader in Mass Data Storage Solutions | Seagate US
- © Contact Us | Seagate US
- 9 Seagate Partners | Seagate US
- 9 Contact Us | Seagate US
- — Warranty & Replacements | Support Seagate US

 — Warranty & Replacements | Support Seagate US
- 9 Software and Firmware Downloads | Support Seagate US
- Product Support | Support Seagate US

Manuals+,